

**High performance probe card analysis without the burden of parametric test system time!**

- Leakage characterization of bare and populated cards.
- Software control by Serial or TCP/IP interfaces.
- Low current, triaxial design.
- Designs for one, two, or four quadrant simultaneous analysis.
- Designs for trace capacitance testing (with an LCR meter).
- Allows sequential and/or selectable access to all probe card traces.
- Allows non-technical staff to operate and perform high resolution, reliable tests.
- Designed for production environments.
- Exhaustive testing in less than an hour for a 48-trace board.

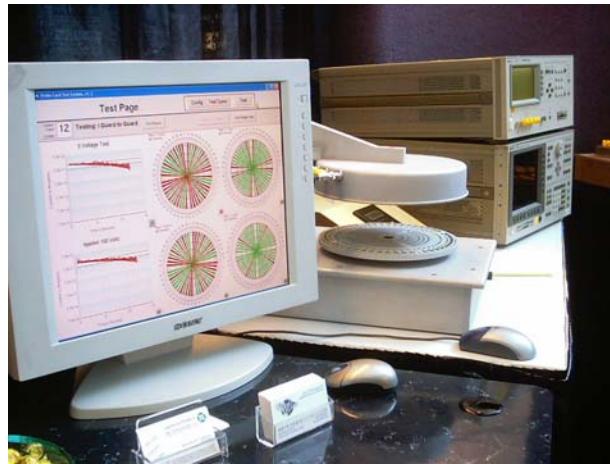
**Supported Instruments:**

- Agilent 4140B
- Agilent 4156A/B/C
- Keithley 6517A
- Keithley 4200

**Probe Cards:**

- Agilent 407X
- Keithley S600

# Probe Card Characterization System



**As seen at Semicon West 2003 (shown with Agilent 4156A and 4285A)**

In the probe card industry, the demand for improved test performance is critical. The PCCS solution can offload probe card certification from the parametric test system to a cost effective, dedicated probe card QC system. The power of the PCCS design is in its software controlled test head, with integrated switch matrix. The tests performed are guarded signal (normal), guard-to-signal, and guard-to-guard leakage currents. These tests are performed and documented using an easy to use software platform. All tests are configured via software for pass/fail criteria, applied voltage, data snapshot window, settle time, and instrument parameters. The software provides password protected levels for specific parameters critical for QC documentation standards. This turn-key system assures easy, error free, and repeatable

characterization of your probe card. The only operator intervention is the loading and unloading of the probe card itself.

The PCCS is comprised of four components: integrated low-leakage switch matrix and trace-probe-head, embedded controller, probe station, and software interface. The probe station provides accurate theta positioning and Z-axis control. Each selected probe card trace is rotated under the trace-probe-head. The Z-movement brings the trace-probe-head in to contact with the selected trace. The imbedded process controller orchestrates the switch matrix with the theta and Z-axis positioning. The probe system is controlled via serial RS232-C or TCP/IP protocol.

The Probe Card Characterization System makes it possible to use your production floor as it was intended - for production.

**Want more info? Call 408/263-3356**

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